

QFET[®]

FQB45N15V2/FQI45N15V2

150V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

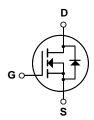
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for DC to DC converters, sychronous rectification, and other applications lowest Rds(on) is required.

Features

- 45A, 150V, $R_{DS(on)} = 0.04\Omega @V_{GS} = 10 V$
- Low gate charge (typical 72 nC)
- Low Crss (typical 135 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability







Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQB45N15V2/FQI45N15V2	Units
V _{DSS}	Drain-Source Voltage		150	V
I _D	Drain Current - Continuous (T _C = 25°C)		45	Α
	- Continuous (T _C = 100°C	;)	31	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	180	Α
V_{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	1124	mJ
I _{AR}	Avalanche Current	(Note 1)	45	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	22	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P _D	Power Dissipation (T _C = 25°C)		220	W
	- Derate above 25°C		1.47	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range	Э	-55 to +175	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics * When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.68	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	6	Min	Тур	Max	Units
Off Cha	racteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA		150			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced	l to 25°C		0.21		V/°C
I _{DSS}	Zana Oata Vallana Basia Oana at	V _{DS} = 150 V, V _{GS} = 0 V				1	μΑ
	Zero Gate Voltage Drain Current	V _{DS} = 120 V, T _C = 150°C	;			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics				1		
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 22.5 \text{ A}$			0.034	0.04	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 22.5 A	(Note 4)		40		S
C _{iss}	Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			2330 510	3030 670	pF pF
C _{rss}	Reverse Transfer Capacitance				135	176	pF
Switchi	ng Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DD} = 75 V, I _D = 45 A,		1	22	54	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		1	232	474	ns
t _{d(off)}	Turn-Off Delay Time	G			224	458	ns
t _f	Turn-Off Fall Time		(Note 4, 5)	1	246	502	ns
Q_g	Total Gate Charge	$V_{DS} = 120 \text{ V}, I_{D} = 45 \text{ A},$			72	94	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 10 V		1	13		nC
Q_{gd}	Gate-Drain Charge		(Note 4, 5)		31		nC
Drain-S	ource Diode Characteristics ar	nd Maximum Rating	s				
I _S	Maximum Continuous Drain-Source Did					45	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	orward Current		1		180	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 45 \text{ A}$		1		1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 45 \text{ A},$		-	176		ns
Q _{rr}	Reverse Recovery Charge	$dI_{F} / dt = 100 A/\mu s$	(Note 4)		1.19		μС

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.74mH, I_{AS} = 45A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq 45A, di/dt \leq 200A/µs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300µs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

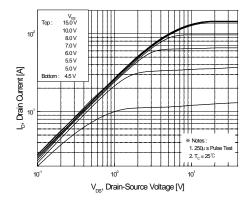


Figure 1. On-Region Characteristics

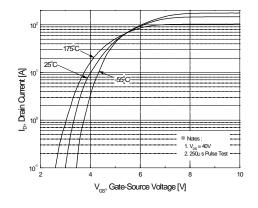


Figure 2. Transfer Characteristics

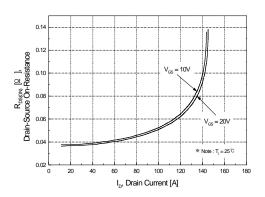


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

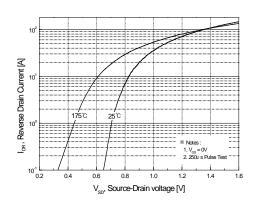


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

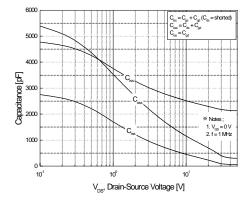


Figure 5. Capacitance Characteristics

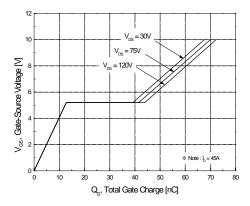


Figure 6. Gate Charge Characteristics

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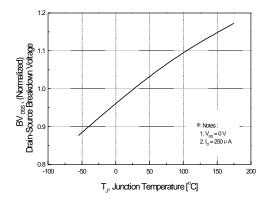


Figure 7. Breakdown Voltage Variation vs Temperature

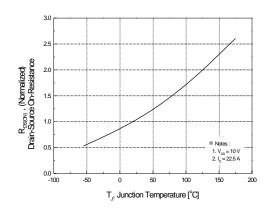


Figure 8. On-Resistance Variation vs Temperature

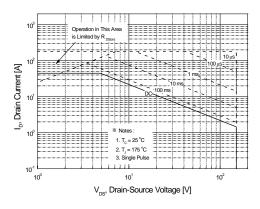


Figure 9. Maximum Safe Operating Area

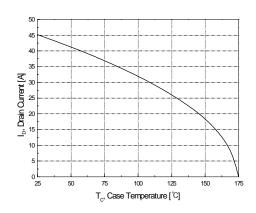


Figure 10. Maximum Drain Current vs Case Temperature

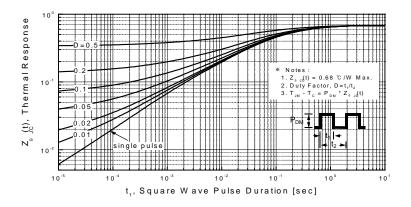
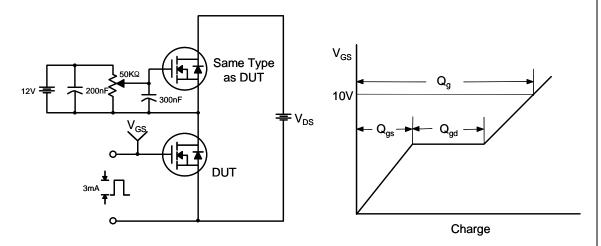


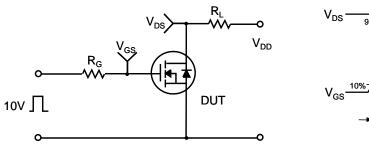
Figure 11. Transient Thermal Response Curve

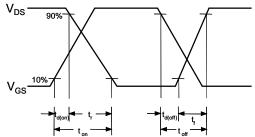
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Gate Charge Test Circuit & Waveform

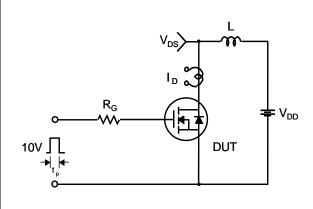


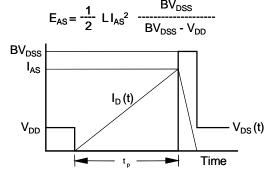
Resistive Switching Test Circuit & Waveforms



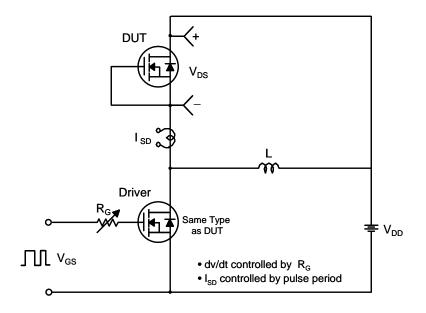


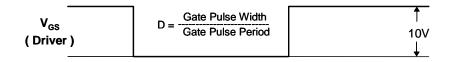
Unclamped Inductive Switching Test Circuit & Waveforms

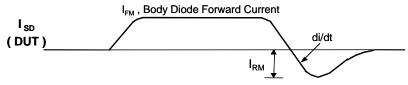




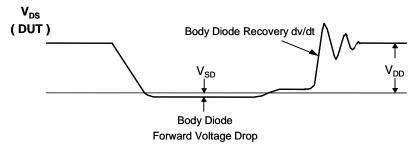
Peak Diode Recovery dv/dt Test Circuit & Waveforms

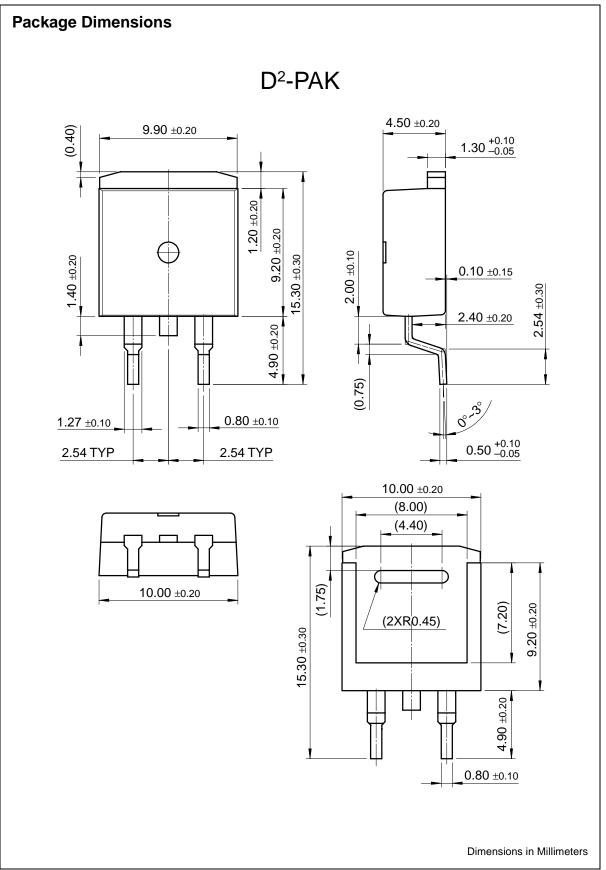


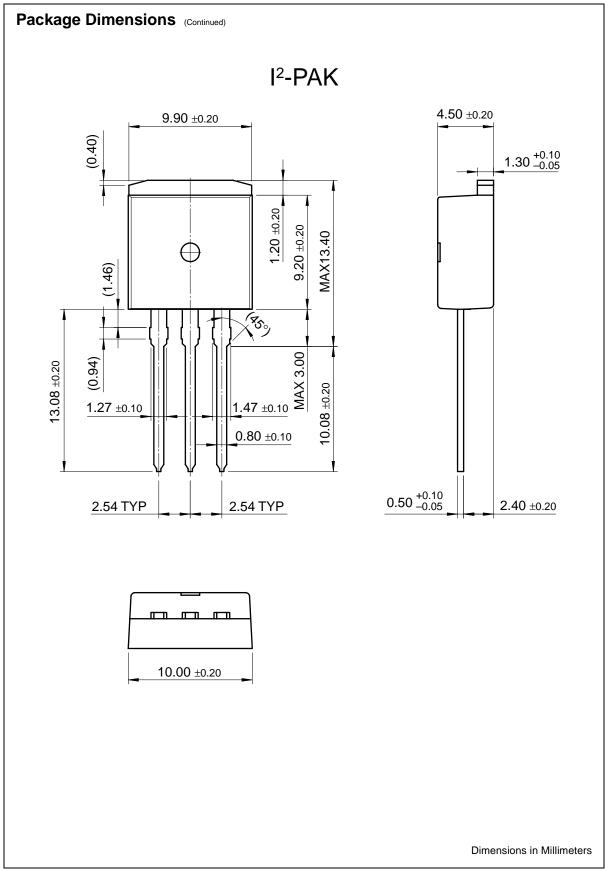




Body Diode Reverse Current







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FQB45N15V2

150V N-Channel Advanced QFET V2 series

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Features

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 - \circ R_{DS(on)} = 0.04 Ω @ V_{GS} = 10V
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Product status/pricing/packaging

BUY

Product	Product status	Pb-free Status	Pricing*	Package type	Leads	Packing method
FQB45N15V2TM	Full Production	Full Production	\$2.14	TO-263(D2PAK)	2	TAPE REEL

^{*} Fairchild 1,000 piece Budgetary Pricing

** A sample button will appear if the part is available through Fairchild's on-line samples program. If there is no sample button, please contact a Fairchild distributor to obtain samples



Indicates product with Pb-free second-level interconnect. For more information click here.

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Qualification Support

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